

# COMPTECH TAB meeting 2015-3

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COMPTECH Officer @ APS, ANL

09/23/2015 Argonne, IL

# Brief introduction

- X-ray Thermal Diffuse Scattering (**TDS**)
  - X-ray thermal diffuse scattering (TDS) can be used to measure: **single-crystal** elastic properties of any crystalline materials (include **opaque materials**) using regular diffraction setups. Incorporation of **DAC** in TDS experiment is possible.
  - New **anisotropic elasticity measurement method** for high-pressure mineral physics field.
- Universal **Membrane cap** for most DACs
  - convert screw-driven DAC into membrane-driven DAC – **remote pressure control**
  - Universal cap that could **fit different DACs without losing DAC opening**
- Standard “cheap” resistive **heater** for DAC
  - **Cheap, reusable**, standard heaters ( $\sim \$10/\text{pc}$  comparing with  $> \$200/\text{pc}$ )
- **Website** Modification
  - **TAB** meeting ppts, Notes
  - **Tools**: including instructions for downloads
  - **Techniques and Facilities**: into to all COMPRES facilities at APS; Updates to technical development
- **Facilities**
  - Sector 34, add-in viewing and optical system for high-pressure experiments

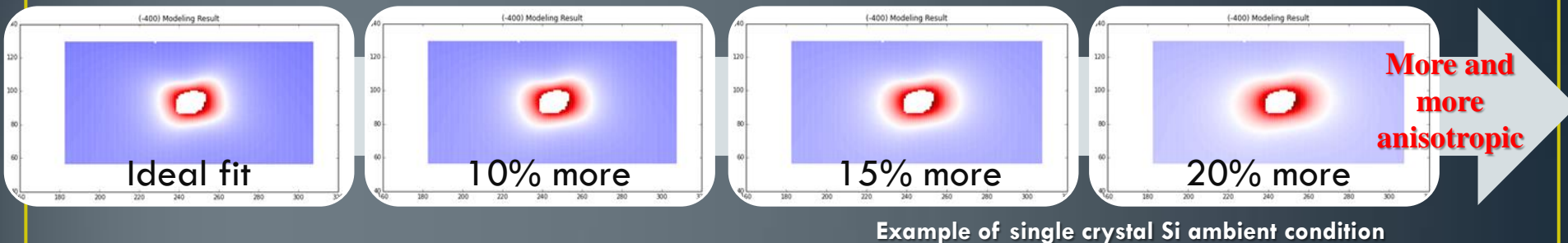
# Time line of COMPTECH



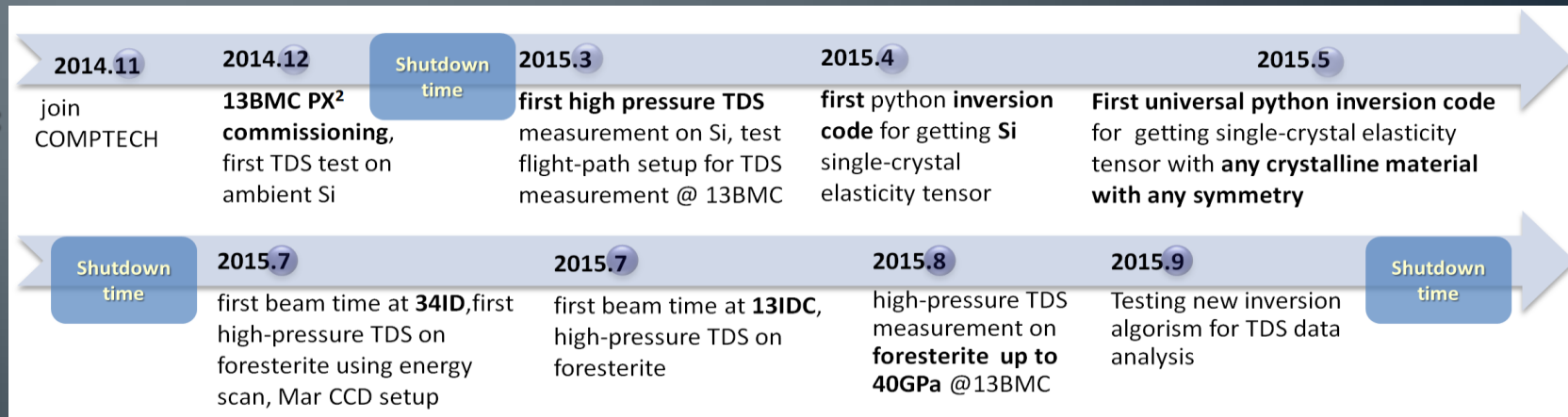
# X-ray thermal diffuse scattering (TDS)

X-ray thermal diffuse scattering (**TDS**) is caused by lattice thermal vibrations (phonons).

**Shape of the TDS signal tells how anisotropic the sound velocities are:**



## Project timeline:



Publication: 2015Fall-2016Spring;

Engaging users: 2016Summer-2016Fall (workshop TDS, collaboration: sample)

New technique: starting 2017Spring (survey in the workshop: XANES XAFS Raman?)

# X-ray thermal diffuse scattering (TDS)

- Current Status:

- Sample testing:

- Ambient condition: Si (100) (111) and **forsterite (111)**
    - High-pressure: Si (100) (1GPa); **forsterite (111) (~40GPa)**

- Experimental Setup:

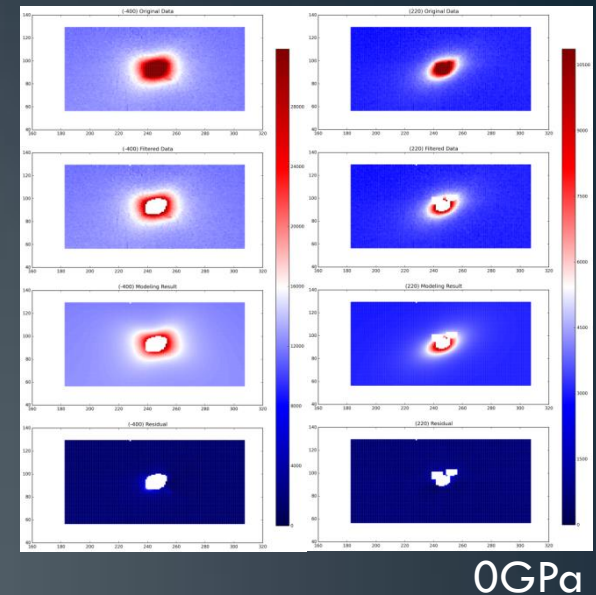
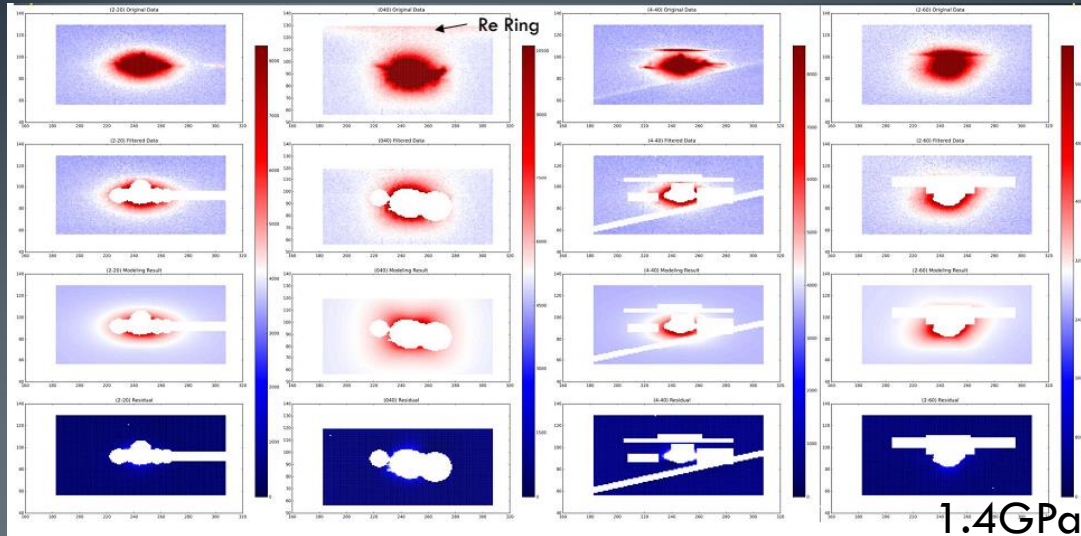
- Using flight path decrease background (originally designed for surface scattering experiment) **13BMC**  
**13IDC (beam size 30μm)**
    - **Energy scan** to find Bragg peaks, then monochromatic beam for TDS measurement (MarCCD) **34ID**

- Software development:

- Python: micro-force-constant model for Si
    - Python: Macro-single crystal elasticity model for crystals with different symmetry
    - Python: new optimized inversion code with **better efficiency** for lower symmetry materials

1 beam time in 2015-1:  
**13BMC**  
3 beam times in 2015-2:  
**13IDC**  
**13BMC**  
**34ID**

- Si



- B. Winkler (U of Frankfurt, 1st principle calculation) (meet during COMPRES 2015 annual meeting)

- $C_{11}=156.6$ ;  $C_{12}=61.2$ ;  $C_{44}=74.6$  @0GPa
- $C_{11}=163.3$ ;  $C_{12}=67.9$ ;  $C_{44}=75.5$  @1.4GPa

- Decremps et al. (PRB 2010) Using phonon imaging up to 7.9GPa

- $C_{11}=165.7$ ;  $C_{12}=63.6$ ;  $C_{44}=80.0$  @0GPa
- $C_{11}=172.1$ ;  $C_{12}=71.5$ ;  $C_{44}=80.0$  @1.4GPa

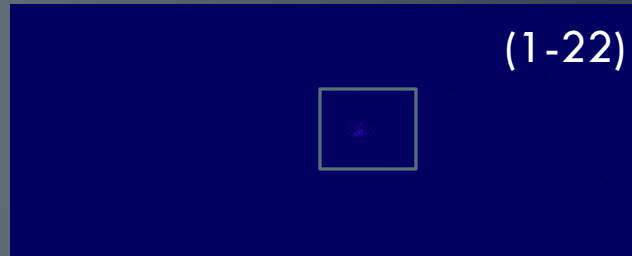
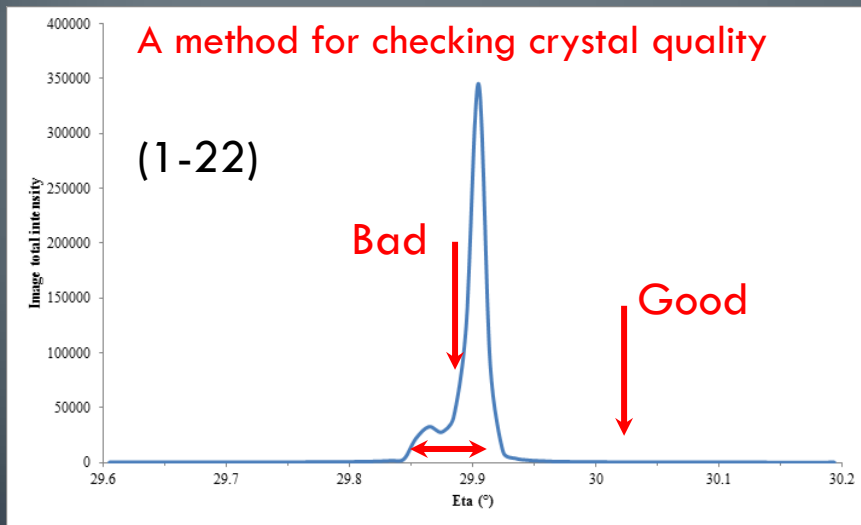
- TDS calculation, this study:

- $C_{11}=166.0(\text{fixed})$ ;  $C_{12}=64.3(\pm 1.6)$ ;  $C_{44}=79.1(\pm 0.8)$  @0GPa
- $C_{11}=172.0(\text{fixed})$ ;  $C_{12}=71.6(\pm 3.1)$ ;  $C_{44}=78.2(\pm 2.7)$  @1.4GPa



# X-ray thermal diffuse scattering (TDS)

- Sample testing:
  - **forsterite (111) low symmetry (orthorhombic) up to ~40GPa**
  - **Geo-materials: silicate**      **He pressure medium VS Ne pressure medium**



Change the Eta angle:  
Off diffraction condition  
to diffraction condition  
to off diffraction condition

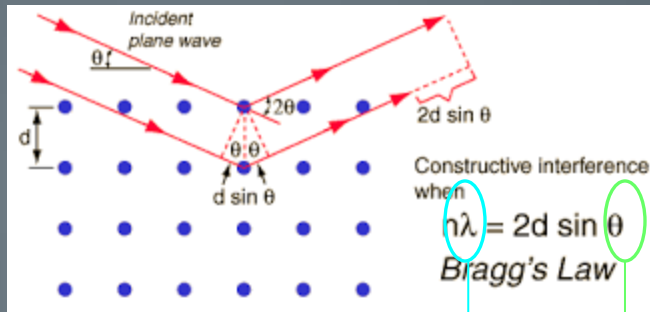
For olivine: ~0.1 up to 25GPa <0.3 ° up to 32GPa <0.5 ° up to 40GPa

- **Accurate determination of orientation matrix (12-20 peaks used instead of just 2)**

Less fitting parameters (No parameter is needed to account for orientation uncertainty)

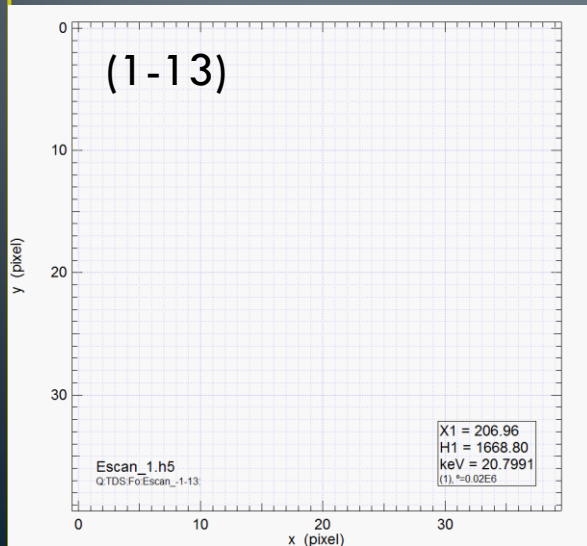
# X-ray thermal diffuse scattering (TDS)

- Sample testing:
  - **Energy scan approach at sector 34**



Beam size <500 nm

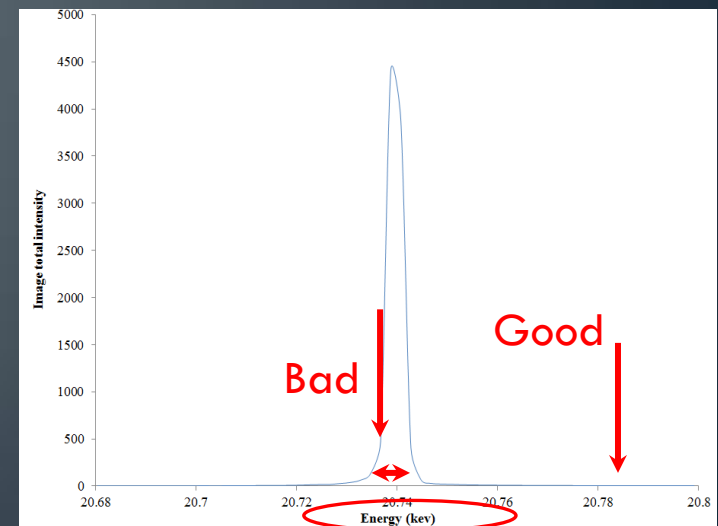
“Bad quality” crystal is not “bad” anymore



34ID

13IDC and BMC

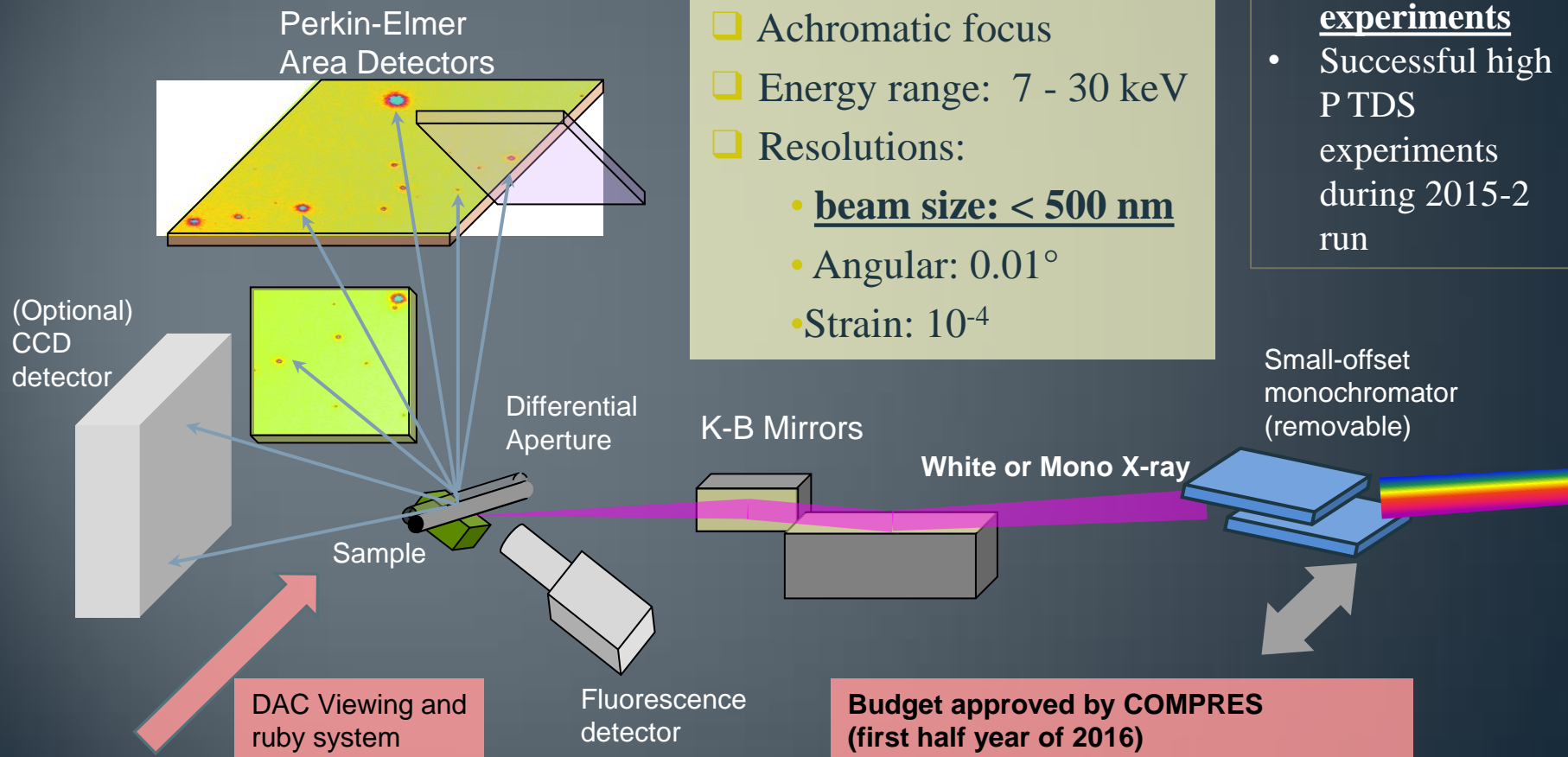
Change the energy:  
Off diffraction condition  
to diffraction condition  
to off diffraction condition





# Preferred access to existing beamlines

## Sector 34 ID



Beamline Contact: Wenjun Liu <wjliu@anl.gov>; Ruqing Xu <ruqingxu@anl.gov>; Jon Tischler <tischler@anl.gov>

# X-ray thermal diffuse scattering (TDS)

- Inversion code development

Only consider 1<sup>st</sup> order approximation – single-phonon scattering

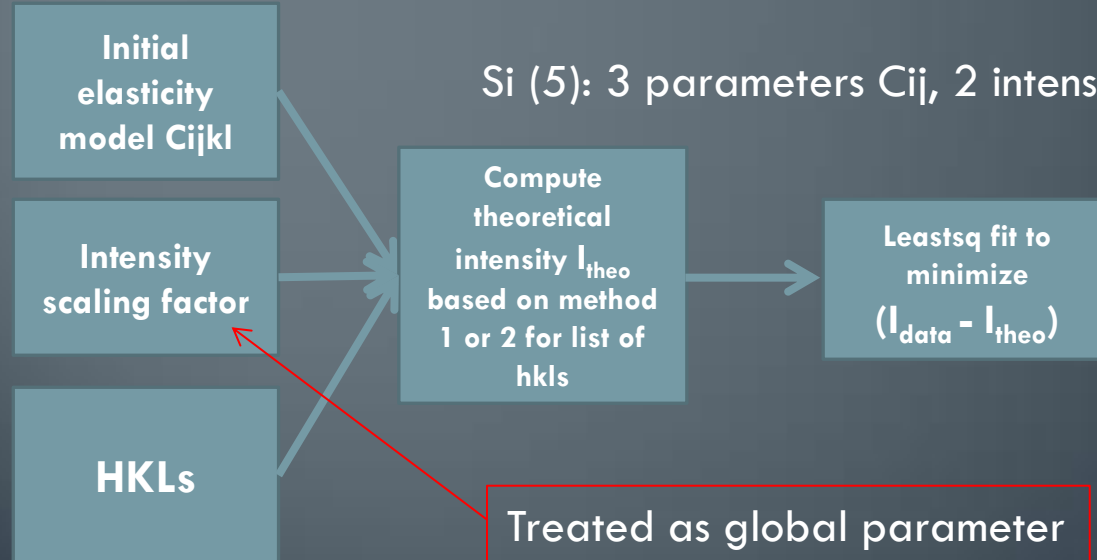
In 2015-2

Method 1: single crystal elasticity model

Method 2: Born-Von-Karman model

1 model for all, only based on  $C_{ij}$ s and hkl's.  
Change  $C_{ij}$ s for different materials.

Micro force constant model for each pair of neighboring atoms – 1 material 1 model



Si (5): 3 parameters  $C_{ij}$ , 2 intensity scaling factors for 2 images

Fo (27):

9 parameters for  $C_{ij}$   
18 intensity scaling factors for 18 TDS images



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- Inversion code development

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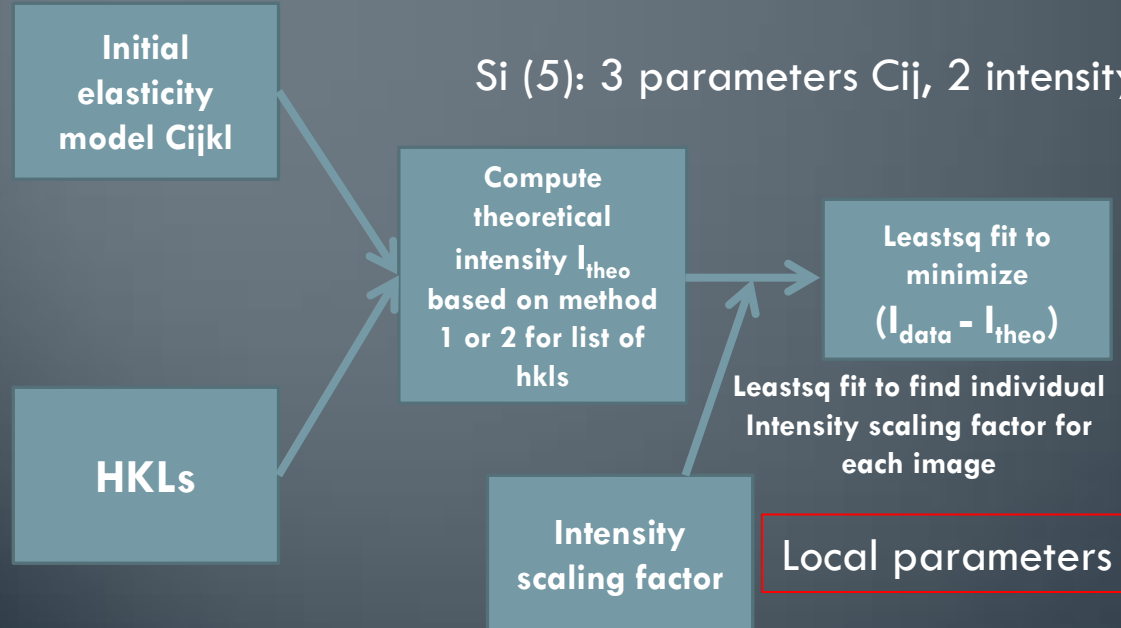
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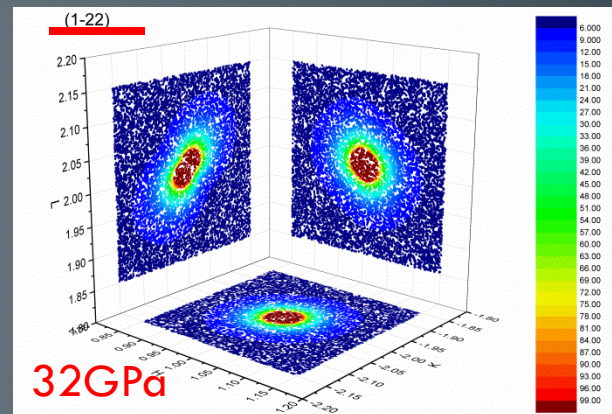
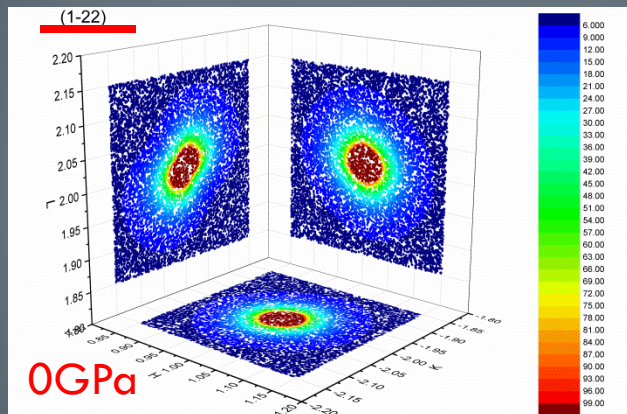
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18 intensity scaling factors for 18 TDS images

Debugging the code now

# X-ray thermal diffuse scattering (TDS)

- **TDS simulation**

- Given elasticity model and HKL simulate the TDS signal



## Future work in last TAB meeting:

✓ **Reduce Error:** sample orientation for the flight path setup – only two bragg peaks are used for orientation determination

~✓ Standard measurement: **bench mark** for high pressure TDS measurement

Software interface: work with professional software engineers

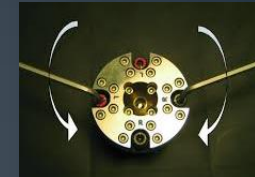
Working with theoreticians: under situation where trade-offs are large (e.g. low symmetry materials), tds only might not yield to a single solution, but will provide extra constrain to theoretical calculation.

High temperature effect

More exciting materials (seeking collaborations and invite users)

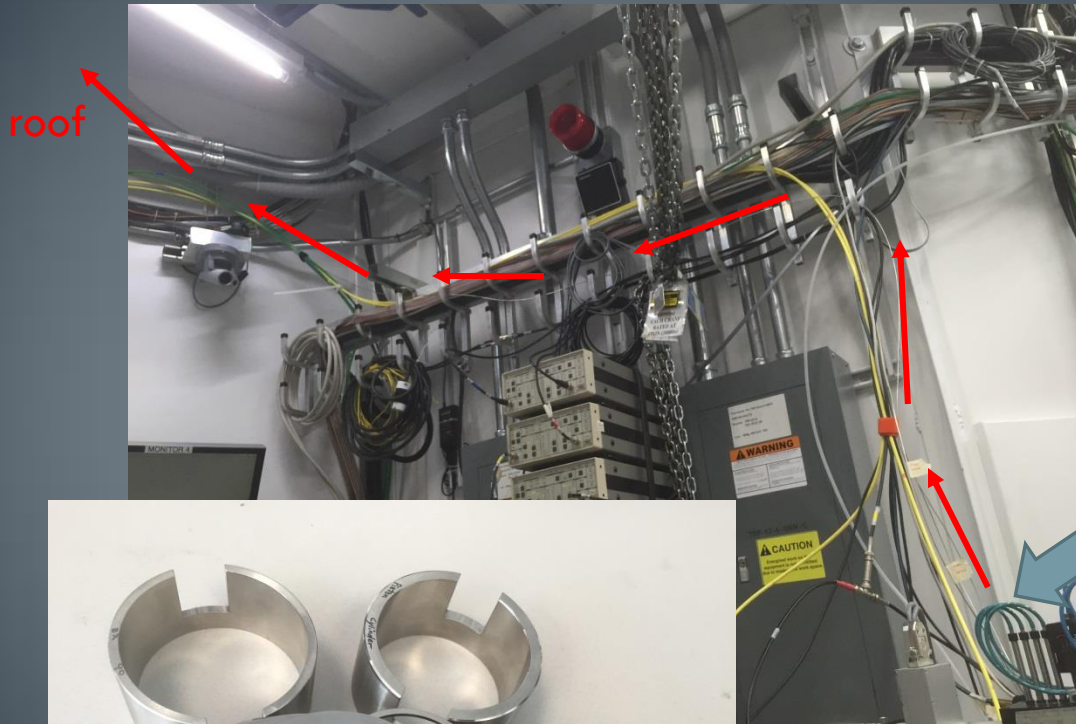
# Universal Membrane cap for most DACs

- Advantage of Membrane cap – convert screw-driven DAC into membrane-driven DAC
- Remote precise pressure control
- Currently available membrane caps
  - Too many DACs in different sizes – one cap for each type
  - Limitations to the DAC opening – IXS, Brillouin, single x-stal XRD
- Our target:
  - **One cap for all** DACs in different sizes: different spacers
  - **No lose in DAC opening**: ideal for single crystal studies
- Project status:
  - Designed the first edition of membrane cap 01/2015
  - Received all body parts of membrane cap 06/2015
  - Stainless steel tubing installed in 13BMC already 07/2015
  - GE digital pressure controller ordered 08/2015
  - Gas membranes sent back to machine shop for revision 09/2015
- Project status:
  - Hopefully will get the membrane and pressure controller by 11/2015
  - Welcome COMPRES users to use!





# Universal Membrane cap for most DACs



Membrane Holder

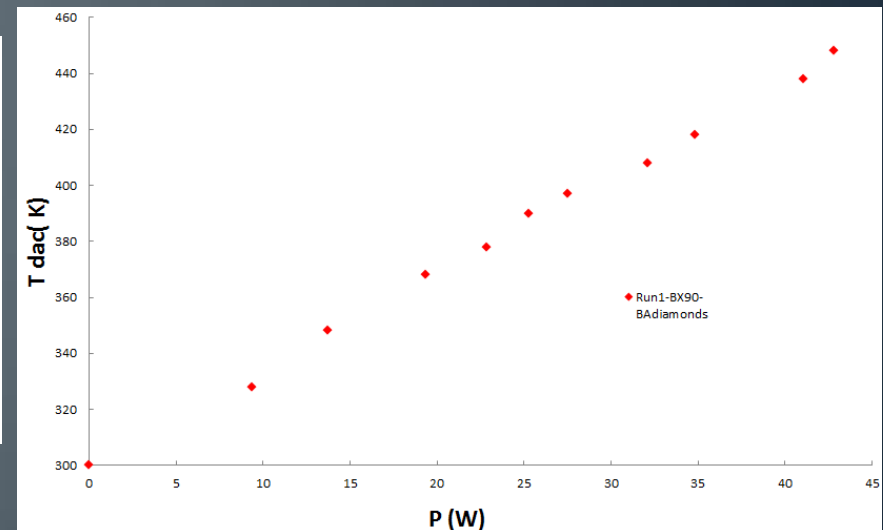
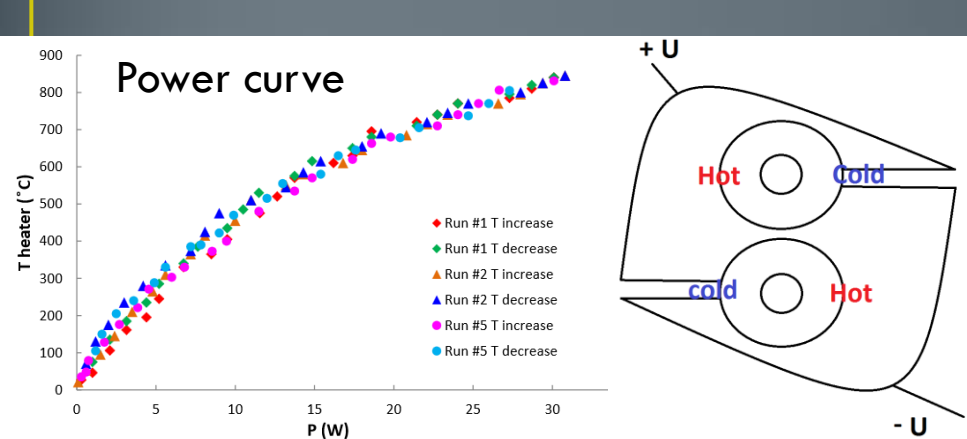
Waiting:

1. Membrane controller
2. Membranes



# Standard “cheap” resistive heater for DAC

- Commercial W-Al<sub>2</sub>O<sub>3</sub> metal ceramics heater can reach 1000 K within 30 s, very stable and cheap (<\$10/pc).
- Ready for use, reproducible specifications, reusable, and not expensive
- Calibration and modification of the W-Al<sub>2</sub>O<sub>3</sub> heater: ([procedures online updated](#))



- Project status:
  - 1<sup>st</sup> test with DAC: with single heater – sample chamber reached highest T 450K
  - 1<sup>st</sup> supply to COMPRES users: University of Arizona (Dan Shim and Kurt Leinenweber)

# Website

<http://comptech.compres.us/>

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## FACILITIES

### ADVANCED PHOTON SOURCE, ARGONNE NATIONAL LABORATORY

#### SECTOR 3 ID-C: SINGLE-CRYSTAL X-RAY EXPERIMENTS FOR SOUND VELOCITY MEASUREMENTS


- Tutorial: single crystal XRD measurements.

#### SECTOR 6 BM-B: A MULTI-ANVIL WHITE BEAM D-DIA FACILITY FOR DEFORMATION EXPERIMENTS

- Information on D-DIA at 6BM-B
- Contact: Haiyan Chen  
Email: haiyan@anl.gov
- Beamline Scientist:  
High Pressure / Multi-anvil Press
- Main Contact: Haiyan Chen  
Sector 6, Advanced Photon Source  
Building 432B, Argonne National Laboratory  
9700 South Cass Ave.  
Argonne, IL 60439

#### SECTOR 13 BM-C: A NEW FACILITY FOR HIGH-PRESSURE SINGLE-CRYSTAL AND POWDER DIFFRACTION EXPERIMENTS


- Information on 13 BM-C
- BMC experimental hutches (pictures from Dr. Dongzhou Zhang)



- Contact: Dongzhou Zhang  
Email: ddzhang@cars.uchicago.edu or dczhang@hawaii.edu
- Beamline Scientist, High Pressure / High Temperature Diamond Anvil Cell (DAC)
- Main Contact: GSECARS, Building 434A, Argonne National Laboratory, 9700 South Cass Ave., Argonne, IL 60439

### GSECARS/COMPRES GAS LOADING SYSTEM

- Information on gas loading system
- Contact: Sergey Tkachev  
Email: tkachev@cars.uchicago.edu
- Beamline Scientist:  
High Pressure / High Temperature Diamond Anvil Cell (DAC)
- Main Contact: GSECARS / COMPRES Gas Loading System  
GSECARS, University of Chicago  
Building 434A, Argonne National Laboratory  
9700 South Cass Ave.  
Argonne, IL 60439  
Phone: 630.252.0430  
Fax: 630.252.0436



## LINKS

### BEAMLINE FACILITIES

- GeoSoilEnviroCARS (APS Sector 13)
- HP-CAT (APS Sector 16), High Pressure Collaborative Access Team
- APS Sector 3, Inelastic X-ray Nuclear Resonant Scattering Group

## STANDARD DAC HEATER


OUR TARGET IS TO DESIGN A HEATER WITH FOLLOWING CHARACTERISTICS:

- Ready for use, minimal work to attach to a DAC.
- Well-calibrated, specifications have to be repeatable from piece to piece
- Reusable and not expensive
- Universal, fits as many types of DACs as possible
- Wide range of temperature if possible

- Commercial tungsten heaters sealed within evacuated ceramic capsules can reach 1000 K within 30 s and are very stable. However their sizes are not suitable for DAC experiments. We plan to redesign the commercial W heaters to fit in the BX-90 cell, modified 3-pin and 4-pin Merrill-Bassett cells, which are the most widely used resistive heated DACs in the mineral physics community.

PROJECT STATUS:

- Test of original W-based heater (lower curves), silicon heating from single heater bonded by gluing two heaters together



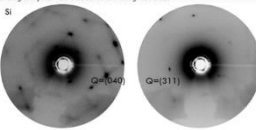
- Instructions for using the originally designed heater available: [Download](#)

Address: 9700 S. CASS AVE., BUILDING 434A, ARGONNE, IL 60439 TEL: (630) 252-0441 COPYRIGHT © 2015 COMPTECH

## TDS EXPERIMENT INVOLVE 3 STEPS:

- Single crystal diffraction to get orientation matrix and unit cell parameters.
- Picking up Bragg peaks with proper  $hkl$  IDs.
- Measuring TDS signal focused on the selected Bragg peaks at slightly off-Bragg condition.

- Si single-crystal TDS measurement using mar CCD:



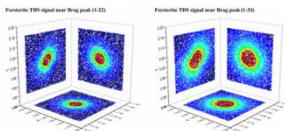
## TDS DATA ANALYSIS INVOLVE 4 STEPS:

- Raw data processing: background subtraction, peak fitting, and data reduction.
- Building micro-force-constant model for studied material, single-crystal elastic constants are independent variables.
- Least square fitting for single crystal elasticity lattice parameters as well as X-ray energy are additional (fixed) input parameters.
- Evaluate fitting quality by comparing the TDS signal calculated from the final fitting model with real experimental data.

PROJECT STATUS:

- Ambient condition measurement: single-crystal Si and MgO.
- High-pressure measurement: single-crystal Si at room temperature and one high pressure in 2015-1 cycle.
- Software: preliminary python-Fortran code developed based least sq fitting.
- High-pressure measurement: single-crystal forsterite at room temperature and one high pressure in 2015-2 cycle.

- Forsterite single-crystal TDS signal:



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## COMPTECH TECHNOLOGY ADVISORY BOARD (TAB)

### TASK OF COMPRES TAB

Technology Advisory Board (TAB) oversees and guides the activities of COMPTECH. The Board is comprised of synchrotron technology experts, members of the central high-pressure facilities (e.g. HP-CAT, GSECARS), managers of the other COMPRES facilities (ALS, NSLS) and mineral physics researchers representing a cross-section of the COMPRES community. President of COMPRES as well as chairs of the two standing committees serve as extra official members of the TAB. TAB meets 3-4 times per year through teleconferencing to discuss the activities and progress of the project as well as to plan future initiatives and actions.

### TAB MEETING AGENDA FOR YEAR OF 2015

- 1st meeting: Jan-15-2015
- 2nd meeting: May-28-2015
- 3rd meeting: Sep-23-2015

### TAB MEETING MINUTES

- 2015 1st meeting:  
powered by Jin Zhang  
Notes by Jin Zhang and Przemek Dera
- 2015 2nd meeting:  
powered by Jin Zhang  
Notes by Jin Zhang and Przemek Dera
- 2015 3rd meeting:

## COMPTECH PEOPLE

- Program Director (Mar 2013 - Now): Dr. Przemek Dera, E-mail: [pdera@hawaii.edu](mailto:pdera@hawaii.edu)
- Chief Technology Officer (Nov. 18 2014 - Now): Dr. Jin Zhang, E-mail: [jnz@hawaii.edu](mailto:jnz@hawaii.edu)
- Previous Chief Technology Officer (Mar 2013 - Dec 2013): Dr. Bin Chen, E-mail: [binchen@hawaii.edu](mailto:binchen@hawaii.edu)

## MEMBERS OF ADVISORY COMMITTEE

### Jan 2015-

- Chair: Dr. Quentin Williams: Department of Earth & Planetary Sciences, University of California at Santa Cruz

Thanks! Questions?